

# RELIABILITY REPORT



## RELIABILITY DATA

### LT927 / LT928 / LT1166 / LT1794 / LT6300 / LT6301

**8/21/2006**

**• OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF FAILURES <sup>(2)</sup>
PLASTIC DIP SSOP/TSSOP	80	9526	9526	80.00	0
	127	0040	0047	90.44	0
	207			170.44	0

**• HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(4)</sup> AT +85°C	NUMBER OF FAILURES
SSOP/TSSOP	10	0127	0127	10.00	0
	10			10.00	0

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP SOIC/SOT/MSOP SSOP/TSSOP	50	0122	0122	1.20	0
	150	0113	0129	51.60	0
	1,108	0045	0534	136.63	0
	1,308			189.43	0

**• TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP SSOP/TSSOP	150	0113	0129	153.30	0
	1,084	0045	0534	326.74	0
	1,234			480.04	0

**• THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SSOP/TSSOP	1,114	0045	0534	324.20	0
	1,114			324.20	0

(1) Assumes Activation Energy = 1.0 Electron Volts  
 (2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 10.79 FITS  
 (3) Mean Time Between Failures in Years = 10,572  
 (4) Assumes 20X Acceleration from 85°C to +131°C  
 Note: 1 FIT = 1 Failure in One Billion Hours.